

**IN THE CLAIMS**

Claim 1 (currently amended): A probe frame assembly of an inspection apparatus for a liquid crystal display device, comprising:

at least two separate probe frame bodies provided above an upper surface of a chuck for simultaneously applying test pattern signals to shorting bars provided on ~~one or more~~ a plurality of liquid crystal display panels disposed on a glass substrate.

Claim 2 (original): The probe frame assembly according to claim 1, wherein each of the probe frame bodies includes:

probe frame contact pins being in contact with the shorting bars;  
a pogo pin set for insertion into a pogo pin contact provided on the chuck for delivering the test pattern signals to the probe frame contact pins;  
a vacuum pad that is drawn to the chuck when a vacuum is applied; and  
an alignment-adjusting member for positioning the pogo pin set to align with the pogo pin contact.

Claim 3 (currently amended): A method of testing a liquid crystal display panel using the probe assembly according to claim 1, the method including:

simultaneously applying the test pattern signals to the shorting bars of the ~~one or more~~ plurality of liquid crystal display panels.

Claim 4 (currently amended): An inspection apparatus for a liquid crystal display device, comprising:

a chuck loaded with a glass substrate having a plurality of one or more liquid crystal display panels;

a multiplex board attached to one side of the chuck for frequency-dividing test pattern signals; and

a probe frame assembly including at least two separate probe frame bodies being provided above an upper surface of the chuck for simultaneously applying the test pattern signals to a shorting bar provided on each of the plurality of one or more liquid crystal display panels.

Claim 5 (currently amended): The inspection apparatus according to claim 4, wherein the probe frame assembly has at least three separate probe frame bodies that simultaneously apply test patterns to the plurality of at least six liquid crystal display panels.

Claim 6 (original): The inspection apparatus according to claim 4, wherein the chuck includes a pogo pin contact including a plurality of contact holes.

Claim 7 (original): The inspection apparatus according to claim 6, further comprising: a cable and a connector for electrically connecting the pogo pin contact to the multiplex board.

Claim 8 (original): The inspection apparatus according to claim 7, wherein the cable and the connector are provided on a side of the chuck.

Claim 9 (original): The inspection apparatus according to claim 4, wherein each of the probe frame bodies includes:

probe frame contact pins in contact with the shorting bars;

a pogo pin set capable of being inserted into a pogo pin contact provided on the chuck for delivering test pattern signals to the probe frame contact pins;

a vacuum pad that is drawn to the chuck when a vacuum is applied; and

an alignment-adjusting member for positioning the pogo pin set to align with a pogo pin contact.

Claim 10 (currently amended): A method of testing a liquid crystal display panel using the probe assembly according to claim 4, the method including:

simultaneously applying the test pattern signals to the shorting bars of the plurality of one or more liquid crystal display panels.

Claim 11 (currently amended): An inspection apparatus for a liquid crystal display device, comprising:

a chuck loaded with a glass substrate having a plurality of one or more liquid crystal display panels;

a multiplex board attached to a side of the chuck to frequency-divide test pattern signals;

a probe frame assembly including at least two separate probe frame bodies being provided above an upper surface of the chuck for simultaneously applying the test pattern signals to a shorting bar provided on each one of the ~~one or more~~ plurality of liquid crystal display panels;

an electro-optical modulator for irradiating a light onto the plurality of ~~one or more~~ liquid crystal display panels; and

a base member for supporting the chuck, the probe frame assembly and the electro-optical modulator.

Claim 12 (currently amended): The inspection apparatus according to claim 11, wherein the probe frame assembly has at least three separate probe frame bodies that simultaneously apply test patterns to the plurality of ~~at least six~~ liquid crystal display panels.

Claim 13 (original): The inspection apparatus according to claim 11, wherein the chuck includes a pogo pin contact each having holes.

Claim 14 (original): The inspection apparatus according to claim 13, further comprising: a cable and a connector for electrically connecting the pogo pin contact to the multiplex board.

Claim 15 (original): The inspection apparatus according to claim 14, wherein the cable and the connector are provided at a side of the chuck.

Claim 16 (original): The inspection apparatus according to claim 11, wherein each of the probe frame bodies includes:

probe frame contact pins being in contact with a shorting bar;

a pogo pin set capable of being inserted into a pogo pin contact provided on the chuck for delivering test pattern signals to the probe frame contact pins;

a vacuum pad that is drawn to the chuck when a vacuum is applied; and

an alignment-adjusting member for positioning the pogo pin set to align with the pogo pin contact.

Claim 17 (currently amended): A method of testing a liquid crystal display panel using the probe assembly according to claim 11, the method including:

simultaneously applying the test pattern signals to the shorting bars of the plurality of one or more liquid crystal display panels.

Claim 18 (currently amended): A method of testing a liquid crystal display panel using a probe frame assembly, the method including:

loading a glass substrate patterned with a plurality of one or more LCD panels onto a chuck;

lowering two or more probe frame bodies on the chuck; and

simultaneously applying test pattern signals to all of the ~~one or more~~ LCD panels.

Claim 19 (original): The method of testing a liquid crystal display panel using a probe frame assembly according to claim 18, wherein each of the probe frame bodies includes:

probe frame contact pins being in contact with a shorting bar;

a pogo pin set capable of being inserted into a pogo pin contact provided on the chuck for delivering test pattern signals to the probe frame contact pins;

a vacuum pad that is drawn to the chuck when a vacuum is applied; and

an alignment-adjusting member for positioning the pogo pin set to align with the pogo pin contact.